

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ISHIKAWA ET AL.	
		Examiner Deborah Yee	Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,755,895	05-1998	Tamehiro et al.	148/336
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	08-209287	08-1996	Japan	Asahi, Hitoshi et al	-----
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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